

Auto Four-Point Probe for Sheet Resistance Measurement

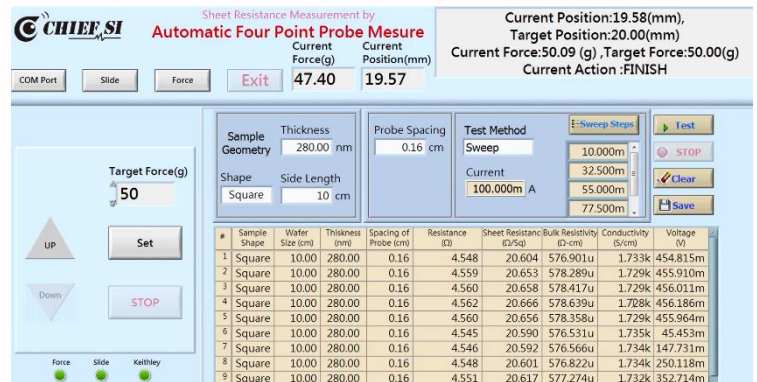


Specifications

Chuck Size	6" , 8" , 12"
Sample Geometry	Circle or Square
Head Up / Down	16mm
Force Control	100g
Correct Factor	Thickness & Geometry
Probe Pin Material	BeCu(or Tungsten Carbide)
Probe Pin Spacing	40mil, 50mil, 62.5mil
Probe Pin Spring	45grams, 85grams, 180grams
Measure Item	Sheet Resistance, Bulk Resistivity, Conductivity
Interface	RS-232 or GPIB
Language	English
PC Requirements	CPU:P4, HD:1GB, USB 2.0
Monitor Requirements	1280*800 resolution
O.S. Supported	WIN7/WIN10
SMU Support	Keithley 2400/2401



Side of the machine



Software

By using four-point probe, measure the Sheet Resistance of different kinds of conductors, semi-conductor in sheet, film, or bulk form. The high-accuracy four-point probe station combined with automatic needle drop and controlled needle force, accurate SMU (Source Measure Unit) provides high quality, easy to use system to measure the Sheet Resistance of thin film materials for various industrial fields such as semi-conductor, solar panel, OLED, MEMS, Fuel Cells, etc.

Features

- Intuitive and easy to use software user interface (UI).
- Automatic needle drop with 100g micro force feedback.
- Accurate measuring the sheet resistance of sample.
- Single or multiple point measuring under constant current.
- Derive the Bulk Resistivity and Conductivity by input the thickness of sample.
- Saving test data by .CSV format for easily handling data.
- Operate with Keithley 2400 SMU by default. Capable of customize software for various SMUs and ohmmeters.

